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### Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	6144
Total RAM Bits	36864
Number of I/O	68
Number of Gates	250000
Voltage - Supply	1.14V ~ 1.575V
Mounting Type	Surface Mount
Operating Temperature	-20°C ~ 85°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/microchip-technology/agln250v2-zvqg100">https://www.e-xfl.com/product-detail/microchip-technology/agln250v2-zvqg100</a>

The inputs of the six CCC blocks are accessible from the FPGA core or from dedicated connections to the CCC block, which are located near the CCC.

The CCC block has these key features:

- Wide input frequency range ( $f_{IN\_CCC}$ ) = 1.5 MHz up to 250 MHz
- Output frequency range ( $f_{OUT\_CCC}$ ) = 0.75 MHz up to 250 MHz
- 2 programmable delay types for clock skew minimization
- Clock frequency synthesis (for PLL only)

Additional CCC specifications:

- Internal phase shift = 0°, 90°, 180°, and 270°. Output phase shift depends on the output divider configuration (for PLL only).
- Output duty cycle = 50%  $\pm$  1.5% or better (for PLL only)
- Low output jitter: worst case < 2.5%  $\times$  clock period peak-to-peak period jitter when single global network used (for PLL only)
- Maximum acquisition time is 300  $\mu$ s (for PLL only)
- Exceptional tolerance to input period jitter—allowable input jitter is up to 1.5 ns (for PLL only)
- Four precise phases; maximum misalignment between adjacent phases of 40 ps  $\times$  250 MHz /  $f_{OUT\_CCC}$  (for PLL only)

### **Global Clocking**

IGLOO nano devices have extensive support for multiple clocking domains. In addition to the CCC and PLL support described above, there is a comprehensive global clock distribution network.

Each VersaTile input and output port has access to nine VersaNets: six chip (main) and three quadrant global networks. The VersaNets can be driven by the CCC or directly accessed from the core via multiplexers (MUXes). The VersaNets can be used to distribute low-skew clock signals or for rapid distribution of high-fanout nets.

### **I/Os with Advanced I/O Standards**

IGLOO nano FPGAs feature a flexible I/O structure, supporting a range of voltages (1.2 V, 1.2 V wide range, 1.5 V, 1.8 V, 2.5 V, 3.0 V wide range, and 3.3 V).

The I/Os are organized into banks with two, three, or four banks per device. The configuration of these banks determines the I/O standards supported.

Each I/O module contains several input, output, and enable registers. These registers allow the implementation of various single-data-rate applications for all versions of nano devices and double-data-rate applications for the AGLN060, AGLN125, and AGLN250 devices.

IGLOO nano devices support LVTTTL and LVCMOS I/O standards, are hot-swappable, and support cold-sparing and Schmitt trigger.

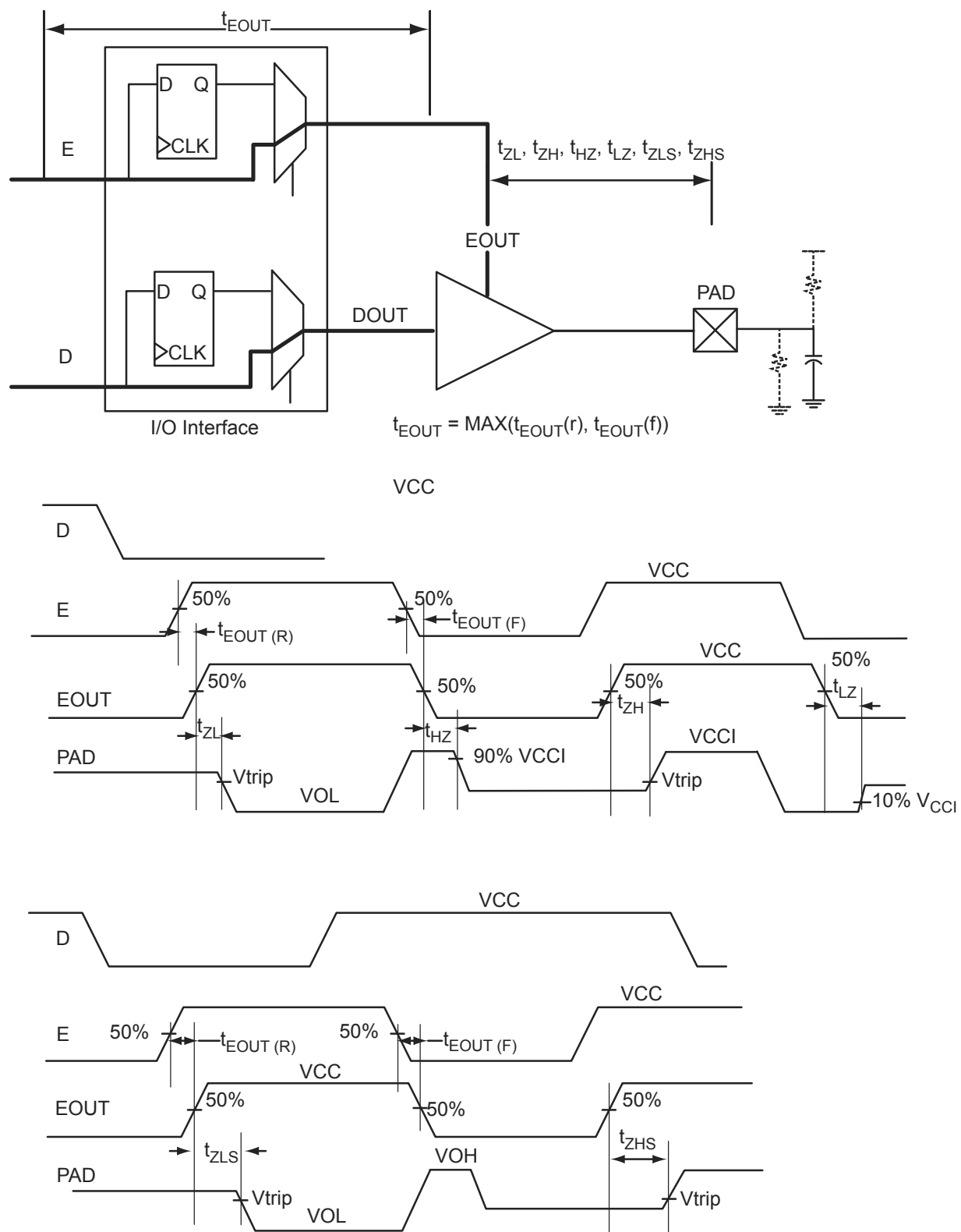
Hot-swap (also called hot-plug, or hot-insertion) is the operation of hot-insertion or hot-removal of a card in a powered-up system.

Cold-sparing (also called cold-swap) refers to the ability of a device to leave system data undisturbed when the system is powered up, while the component itself is powered down, or when power supplies are floating.

### **Wide Range I/O Support**

IGLOO nano devices support JEDEC-defined wide range I/O operation. IGLOO nano devices support both the JESD8-B specification, covering both 3 V and 3.3 V supplies, for an effective operating range of 2.7 V to 3.6 V, and JESD8-12 with its 1.2 V nominal, supporting an effective operating range of 1.14 V to 1.575 V.

Wider I/O range means designers can eliminate power supplies or power conditioning components from the board or move to less costly components with greater tolerances. Wide range eases I/O bank management and provides enhanced protection from system voltage spikes, while providing the flexibility to easily run custom voltage applications.



**Figure 2-6 • Tristate Output Buffer Timing Model and Delays (example)**

**Applies to IGLOO nano at 1.5 V Core Operating Conditions**

**Table 2-25 • Summary of I/O Timing Characteristics—Software Default Settings**  
**STD Speed Grade, Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case VCC = 1.425 V,**  
**Worst-Case VCCI = 3.0 V**

I/O Standard	Drive Strength (mA)	Equivalent Software Default t Drive Strength Option <sup>1</sup>	Slew Rate	Capacitive Load (pF)	t <sub>POUT</sub>	t <sub>DP</sub>	t <sub>DIN</sub>	t <sub>py</sub>	t <sub>pys</sub>	t <sub>EOU</sub>	t <sub>ZL</sub>	t <sub>ZH</sub>	t <sub>LZ</sub>	t <sub>HZ</sub>	Units
3.3 V LVTTTL / 3.3 V LVCMOS	8 mA	8 mA	High	5 pF	0.97	1.79	0.19	0.86	1.16	0.66	1.83	1.45	1.98	2.38	ns
3.3 V LVCMOS Wide Range <sup>2</sup>	100 $\mu\text{A}$	8 mA	High	5 pF	0.97	2.56	0.19	1.20	1.66	0.66	2.57	2.02	2.82	3.31	ns
2.5 V LVCMOS	8 mA	8 mA	High	5 pF	0.97	1.81	0.19	1.10	1.24	0.66	1.85	1.63	1.97	2.26	ns
1.8 V LVCMOS	4 mA	4 mA	High	5 pF	0.97	2.08	0.19	1.03	1.44	0.66	2.12	1.95	1.99	2.19	ns
1.5 V LVCMOS	2 mA	2 mA	High	5 pF	0.97	2.39	0.19	1.19	1.52	0.66	2.44	2.24	2.02	2.15	ns

**Notes:**

1. The minimum drive strength for any LVCMOS 1.2 V or LVCMOS 3.3 V software configuration when run in wide range is  $\pm 100 \mu\text{A}$ . Drive strength displayed in the software is supported for normal range only. For a detailed I/V curve, refer to the IBIS models.
2. All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range, as specified in the JESD8-B specification.
3. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

The length of time an I/O can withstand IOSH/IOSL events depends on the junction temperature. The reliability data below is based on a 3.3 V, 8 mA I/O setting, which is the worst case for this type of analysis.

For example, at 100°C, the short current condition would have to be sustained for more than six months to cause a reliability concern. The I/O design does not contain any short circuit protection, but such protection would only be needed in extremely prolonged stress conditions.

**Table 2-31 • Duration of Short Circuit Event before Failure**

Temperature	Time before Failure
–40°C	> 20 years
–20°C	> 20 years
0°C	> 20 years
25°C	> 20 years
70°C	5 years
85°C	2 years
100°C	6 months

**Table 2-32 • Schmitt Trigger Input Hysteresis  
Hysteresis Voltage Value (Typ.) for Schmitt Mode Input Buffers**

Input Buffer Configuration	Hysteresis Value (typ.)
3.3 V LVTTTL / LVCMOS (Schmitt trigger mode)	240 mV
2.5 V LVCMOS (Schmitt trigger mode)	140 mV
1.8 V LVCMOS (Schmitt trigger mode)	80 mV
1.5 V LVCMOS (Schmitt trigger mode)	60 mV
1.2 V LVCMOS (Schmitt trigger mode)	40 mV

**Table 2-33 • I/O Input Rise Time, Fall Time, and Related I/O Reliability**

Input Buffer	Input Rise/Fall Time (min.)	Input Rise/Fall Time (max.)	Reliability
LVTTTL/LVCMOS (Schmitt trigger disabled)	No requirement	10 ns *	20 years (100°C)
LVTTTL/LVCMOS (Schmitt trigger enabled)	No requirement	No requirement, but input noise voltage cannot exceed Schmitt hysteresis.	20 years (100°C)

*Note: \*The maximum input rise/fall time is related to the noise induced into the input buffer trace. If the noise is low, then the rise time and fall time of input buffers can be increased beyond the maximum value. The longer the rise/fall times, the more susceptible the input signal is to the board noise. Microsemi recommends signal integrity evaluation/characterization of the system to ensure that there is no excessive noise coupling into input signals.*

## 1.8 V LVCMOS

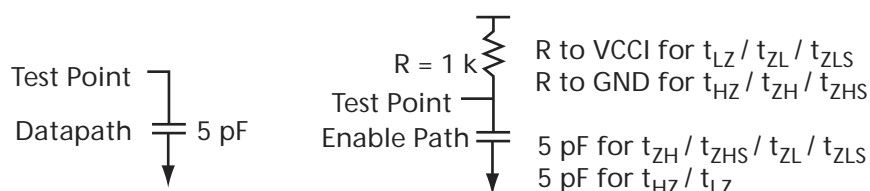
Low-voltage CMOS for 1.8 V is an extension of the LVCMOS standard (JESD8-5) used for general purpose 1.8 V applications. It uses a 1.8 V input buffer and a push-pull output buffer.

**Table 2-51 • Minimum and Maximum DC Input and Output Levels**

1.8 V LVCMOS	VIL		VIH		VOL	VOH	IOL	IOH	IOSL	IOSH	IIL <sup>1</sup>	I <sub>IH</sub> <sup>2</sup>
Drive Strength	Min. V	Max. V	Min. V	Max. V	Max. V	Min. V	mA	mA	Max. mA <sup>3</sup>	Max. mA <sup>3</sup>	μA <sup>4</sup>	μA <sup>4</sup>
2 mA	−0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI − 0.45	2	2	9	11	10	10
4 mA	−0.3	0.35 * VCCI	0.65 * VCCI	3.6	0.45	VCCI − 0.45	4	4	17	22	10	10

Notes:

1.  $I_{IL}$  is the input leakage current per I/O pin over recommended operating conditions where  $-0.3 < V_{IN} < V_{IL}$ .
2.  $I_{IH}$  is the input leakage current per I/O pin over recommended operating conditions where  $V_{IH} < V_{IN} < V_{CCI}$ . Input current is larger when operating outside recommended ranges.
3. Currents are measured at high temperature (100°C junction temperature) and maximum voltage.
4. Currents are measured at 85°C junction temperature.
5. Software default selection highlighted in gray.



**Figure 2-9 • AC Loading**

**Table 2-52 • 1.8 V LVCMOS AC Waveforms, Measuring Points, and Capacitive Loads**

Input LOW (V)	Input HIGH (V)	Measuring Point* (V)	C <sub>LOAD</sub> (pF)
0	1.8	0.9	5

Note: \*Measuring point =  $V_{trip}$ . See Table 2-23 on page 2-20 for a complete table of trip points.

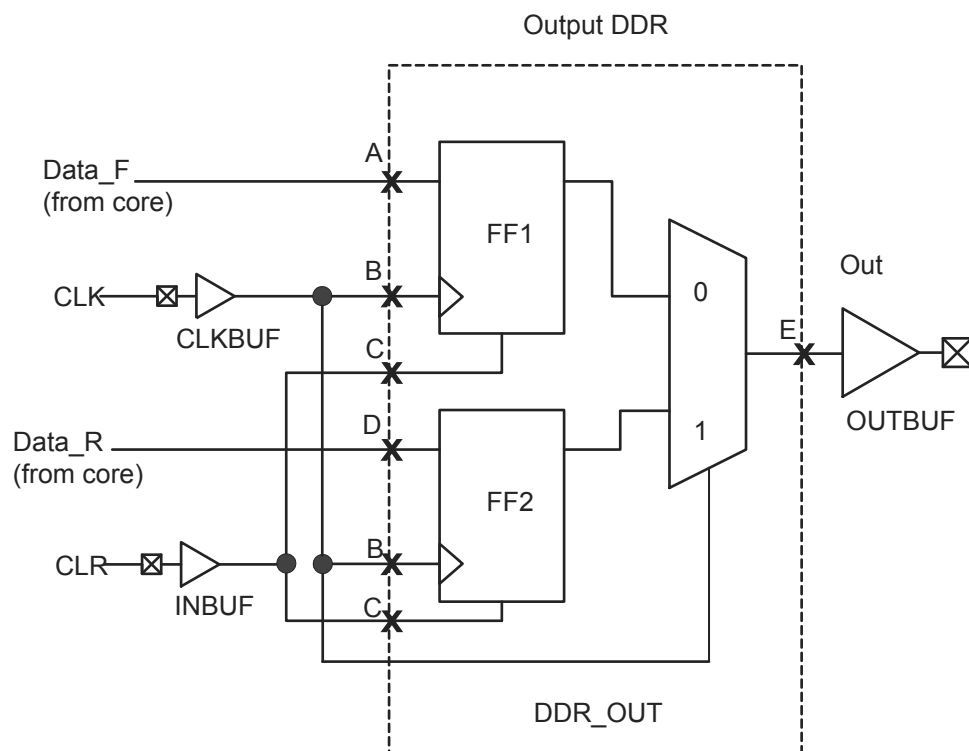
### 1.2 V DC Core Voltage

**Table 2-75 • Output Data Register Propagation Delays**  
Commercial-Case Conditions:  $T_J = 70^{\circ}\text{C}$ , Worst-Case  $V_{CC} = 1.14\text{ V}$

Parameter	Description	Std.	Units
$t_{\text{OCLKQ}}$	Clock-to-Q of the Output Data Register	1.52	ns
$t_{\text{OSUD}}$	Data Setup Time for the Output Data Register	1.15	ns
$t_{\text{OHD}}$	Data Hold Time for the Output Data Register	0.00	ns
$t_{\text{OCLR2Q}}$	Asynchronous Clear-to-Q of the Output Data Register	1.96	ns
$t_{\text{OPRE2Q}}$	Asynchronous Preset-to-Q of the Output Data Register	1.96	ns
$t_{\text{OREMCLR}}$	Asynchronous Clear Removal Time for the Output Data Register	0.00	ns
$t_{\text{ORECCLR}}$	Asynchronous Clear Recovery Time for the Output Data Register	0.24	ns
$t_{\text{OREMPRE}}$	Asynchronous Preset Removal Time for the Output Data Register	0.00	ns
$t_{\text{ORECPRE}}$	Asynchronous Preset Recovery Time for the Output Data Register	0.24	ns
$t_{\text{OWCLR}}$	Asynchronous Clear Minimum Pulse Width for the Output Data Register	0.19	ns
$t_{\text{OWPRE}}$	Asynchronous Preset Minimum Pulse Width for the Output Data Register	0.19	ns
$t_{\text{OCKMPWH}}$	Clock Minimum Pulse Width HIGH for the Output Data Register	0.31	ns
$t_{\text{OCKMPWL}}$	Clock Minimum Pulse Width LOW for the Output Data Register	0.28	ns

*Note:* For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

## Output DDR Module

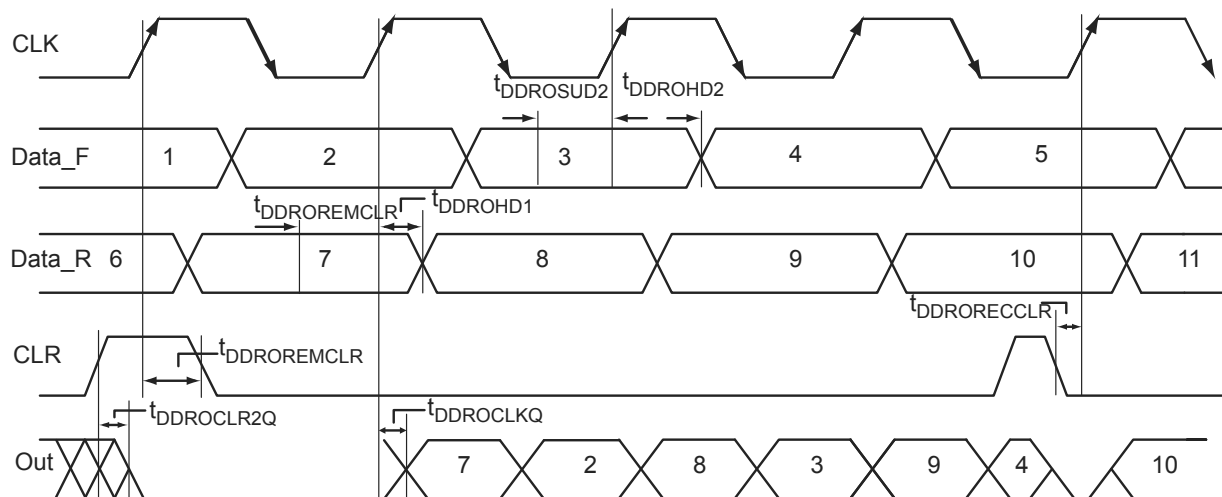


**Figure 2-19 • Output DDR Timing Model**

**Table 2-81 • Parameter Definitions**

Parameter Name	Parameter Definition	Measuring Nodes (from, to)
$t_{\text{DDROCLKQ}}$	Clock-to-Out	B, E
$t_{\text{DDROCLR2Q}}$	Asynchronous Clear-to-Out	C, E
$t_{\text{DDROREMCLR}}$	Clear Removal	C, B
$t_{\text{DDRORECCLR}}$	Clear Recovery	C, B
$t_{\text{DDROSUD1}}$	Data Setup Data_F	A, B
$t_{\text{DDROSUD2}}$	Data Setup Data_R	D, B
$t_{\text{DDROHD1}}$	Data Hold Data_F	A, B
$t_{\text{DDROHD2}}$	Data Hold Data_R	D, B





**Figure 2-20 • Output DDR Timing Diagram**

### Timing Characteristics

#### 1.5 V DC Core Voltage

**Table 2-82 • Output DDR Propagation Delays**  
Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ , Worst-Case  $V_{CC} = 1.425\text{ V}$

Parameter	Description	Std.	Units
$t_{\text{DDROCLKQ}}$	Clock-to-Out of DDR for Output DDR	1.07	ns
$t_{\text{DDROSUD1}}$	Data_F Data Setup for Output DDR	0.67	ns
$t_{\text{DDROSUD2}}$	Data_R Data Setup for Output DDR	0.67	ns
$t_{\text{DDROHD1}}$	Data_F Data Hold for Output DDR	0.00	ns
$t_{\text{DDROHD2}}$	Data_R Data Hold for Output DDR	0.00	ns
$t_{\text{DDROCLR2Q}}$	Asynchronous Clear-to-Out for Output DDR	1.38	ns
$t_{\text{DDROEMCLR}}$	Asynchronous Clear Removal Time for Output DDR	0.00	ns
$t_{\text{DDROECCLR}}$	Asynchronous Clear Recovery Time for Output DDR	0.23	ns
$t_{\text{DDROWCLR1}}$	Asynchronous Clear Minimum Pulse Width for Output DDR	0.19	ns
$t_{\text{DDROCKMPWH}}$	Clock Minimum Pulse Width HIGH for the Output DDR	0.31	ns
$t_{\text{DDROCKMPWL}}$	Clock Minimum Pulse Width LOW for the Output DDR	0.28	ns
$F_{\text{DDOMAX}}$	Maximum Frequency for the Output DDR	250.00	MHz

*Note:* For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 for derating values.

## 1.2 V DC Core Voltage

**Table 2-87 • Register Delays**  
Commercial-Case Conditions:  $T_J = 70^{\circ}\text{C}$ , Worst-Case  $V_{CC} = 1.14\text{ V}$

Parameter	Description	Std.	Units
$t_{\text{CLKQ}}$	Clock-to-Q of the Core Register	1.61	ns
$t_{\text{SUD}}$	Data Setup Time for the Core Register	1.17	ns
$t_{\text{HD}}$	Data Hold Time for the Core Register	0.00	ns
$t_{\text{SUE}}$	Enable Setup Time for the Core Register	1.29	ns
$t_{\text{HE}}$	Enable Hold Time for the Core Register	0.00	ns
$t_{\text{CLR2Q}}$	Asynchronous Clear-to-Q of the Core Register	0.87	ns
$t_{\text{PRE2Q}}$	Asynchronous Preset-to-Q of the Core Register	0.89	ns
$t_{\text{REMCLR}}$	Asynchronous Clear Removal Time for the Core Register	0.00	ns
$t_{\text{RECCLR}}$	Asynchronous Clear Recovery Time for the Core Register	0.24	ns
$t_{\text{REMPRE}}$	Asynchronous Preset Removal Time for the Core Register	0.00	ns
$t_{\text{RECPRE}}$	Asynchronous Preset Recovery Time for the Core Register	0.24	ns
$t_{\text{WCLR}}$	Asynchronous Clear Minimum Pulse Width for the Core Register	0.46	ns
$t_{\text{WPRE}}$	Asynchronous Preset Minimum Pulse Width for the Core Register	0.46	ns
$t_{\text{CKMPWH}}$	Clock Minimum Pulse Width HIGH for the Core Register	0.95	ns
$t_{\text{CKMPWL}}$	Clock Minimum Pulse Width LOW for the Core Register	0.95	ns

*Note:* For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

**Table 2-98 • AGLN125 Global Resource**  
**Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ ,  $V_{CC} = 1.14\text{ V}$**

Parameter	Description	Std.		Units
		Min. <sup>1</sup>	Max. <sup>2</sup>	
$t_{RCKL}$	Input Low Delay for Global Clock	2.08	2.54	ns
$t_{RCKH}$	Input High Delay for Global Clock	2.15	2.77	ns
$t_{RCKMPWH}$	Minimum Pulse Width HIGH for Global Clock	1.40		ns
$t_{RCKMPWL}$	Minimum Pulse Width LOW for Global Clock	1.65		ns
$t_{RCKSW}$	Maximum Skew for Global Clock		0.62	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

**Table 2-99 • AGLN250 Global Resource**  
**Commercial-Case Conditions:  $T_J = 70^\circ\text{C}$ ,  $V_{CC} = 1.14\text{ V}$**

Parameter	Description	Std.		Units
		Min. <sup>1</sup>	Max. <sup>2</sup>	
$t_{RCKL}$	Input Low Delay for Global Clock	2.11	2.57	ns
$t_{RCKH}$	Input High Delay for Global Clock	2.19	2.81	ns
$t_{RCKMPWH}$	Minimum Pulse Width High for Global Clock	1.40		ns
$t_{RCKMPWL}$	Minimum Pulse Width Low for Global Clock	1.65		ns
$t_{RCKSW}$	Maximum Skew for Global Clock		0.62	ns

Notes:

1. Value reflects minimum load. The delay is measured from the CCC output to the clock pin of a sequential element, located in a lightly loaded row (single element is connected to the global net).
2. Value reflects maximum load. The delay is measured on the clock pin of the farthest sequential element, located in a fully loaded row (all available flip-flops are connected to the global net in the row).
3. For specific junction temperature and voltage supply levels, refer to Table 2-7 on page 2-7 for derating values.

## Clock Conditioning Circuits

### CCC Electrical Specifications

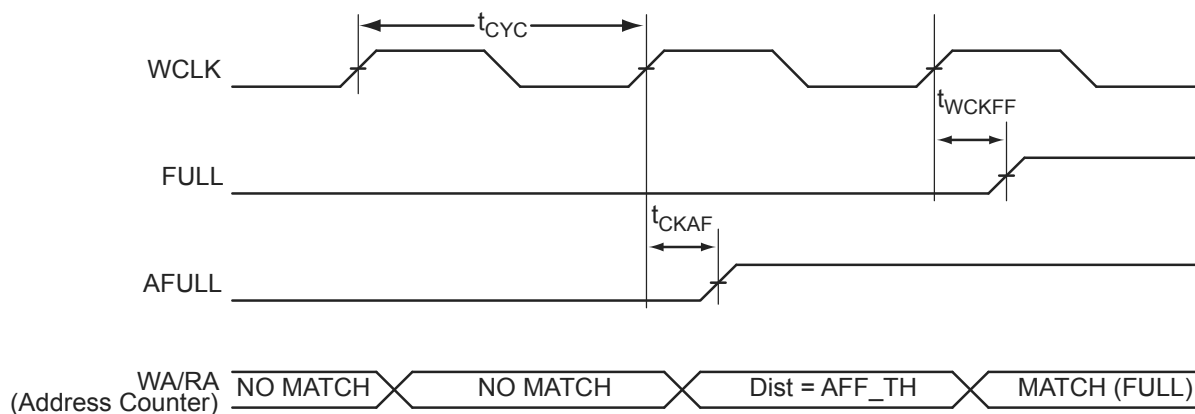
#### Timing Characteristics

**Table 2-100 • IGLOO nano CCC/PLL Specification**  
For IGLOO nano V2 OR V5 Devices, 1.5 V DC Core Supply Voltage

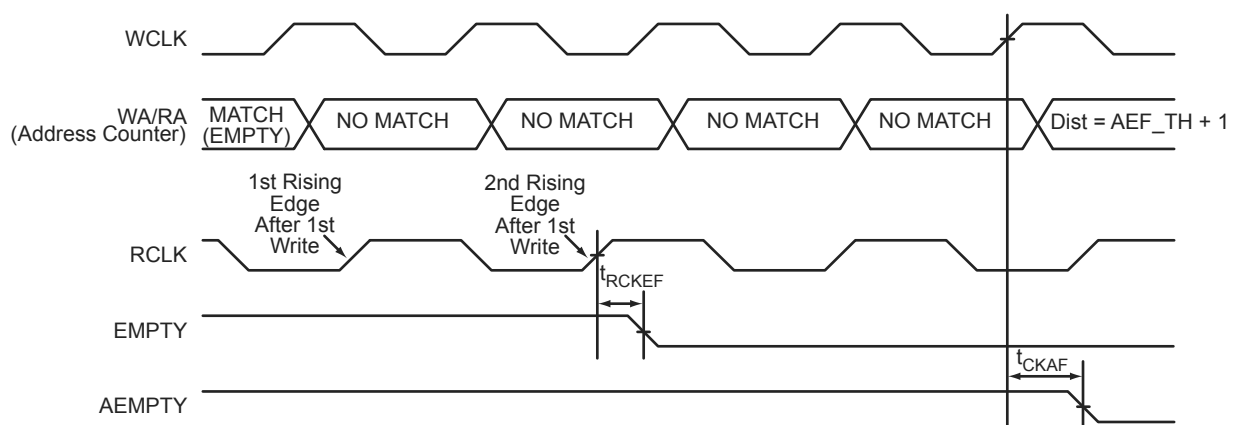
Parameter		Min.	Typ.	Max.	Units	
Clock Conditioning Circuitry Input Frequency $f_{IN\_CCC}$		1.5		250	MHz	
Clock Conditioning Circuitry Output Frequency $f_{OUT\_CCC}$		0.75		250	MHz	
Delay Increments in Programmable Delay Blocks <sup>1, 2</sup>			360 <sup>3</sup>		ps	
Number of Programmable Values in Each Programmable Delay Block				32		
Serial Clock (SCLK) for Dynamic PLL <sup>4,9</sup>				100	MHz	
Input Cycle-to-Cycle Jitter (peak magnitude)				1	ns	
Acquisition Time	LockControl = 0  LockControl = 1					
				300	μs	
				6.0	ms	
Tracking Jitter <sup>5</sup>	LockControl = 0  LockControl = 1					
				2.5	ns	
				1.5	ns	
Output Duty Cycle		48.5		51.5	%	
Delay Range in Block: Programmable Delay 1 <sup>1, 2</sup>		1.25		15.65	ns	
Delay Range in Block: Programmable Delay 2 <sup>1, 2,</sup>		0.025		15.65	ns	
Delay Range in Block: Fixed Delay <sup>1, 2</sup>			3.5		ns	
VCO Output Peak-to-Peak Period Jitter $F_{CCC\_OUT}$ <sup>6</sup>		Max Peak-to-Peak Jitter Data <sup>6,7,8</sup>				
	SSO ≤ 2	SSO ≤ 4	SSO ≤ 8	SSO ≤ 16		
0.75 MHz to 50 MHz		0.50	0.60	0.80	1.20	%
50 MHz to 250 MHz		2.50	4.00	6.00	12.00	%

**Notes:**

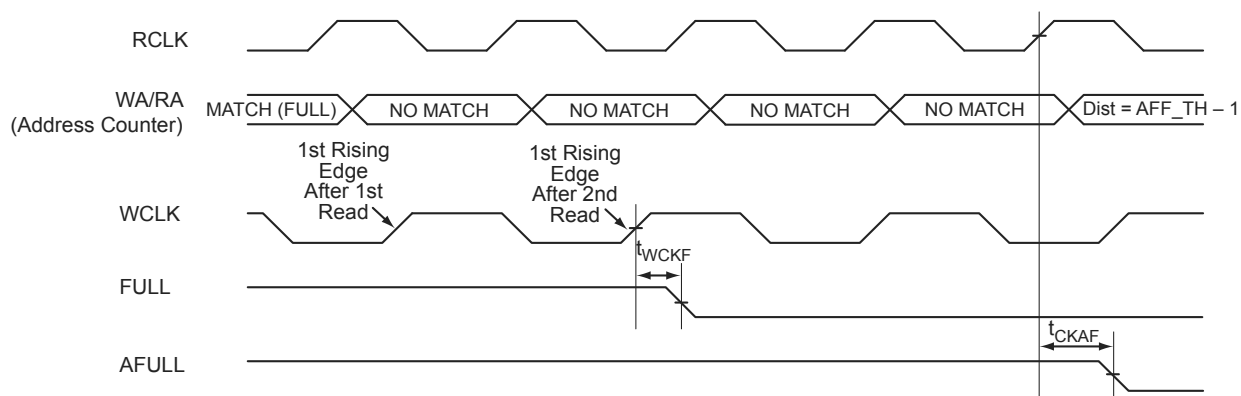
1. This delay is a function of voltage and temperature. See Table 2-6 on page 2-6 and Table 2-7 on page 2-7 for deratings.
2.  $T_J = 25^\circ\text{C}$ ,  $V_{CC} = 1.5\text{ V}$
3. When the CCC/PLL core is generated by Microsemi core generator software, not all delay values of the specified delay increments are available. Refer to the Libero SoC Online Help associated with the core for more information.
4. Maximum value obtained for a STD speed grade device in Worst-Case Commercial conditions. For specific junction temperature and voltage supply levels, refer to Table 2-6 on page 2-6 and Table 2-7 on page 2-7 for derating values.
5. Tracking jitter is defined as the variation in clock edge position of PLL outputs with reference to PLL input clock edge. Tracking jitter does not measure the variation in PLL output period, which is covered by the period jitter parameter.
6. VCO output jitter is calculated as a percentage of the VCO frequency. The jitter (in ps) can be calculated by multiplying the VCO period by the % jitter. The VCO jitter (in ps) applies to CCC\_OUT, regardless of the output divider settings. For example, if the jitter on VCO is 300 ps, the jitter on CCC\_OUT is also 300 ps, no matter what the settings are for the output divider.
7. Measurements done with LVTTTL 3.3 V 8 mA I/O drive strength and high slew rate.  $V_{CC}/V_{CCPLL} = 1.425\text{ V}$ ,  $V_{CCI} = 3.3\text{ V}$ , VQ/PQ/TQ type of packages, 20 pF load.
8. SSOs are outputs that are synchronous to a single clock domain and have their clock-to-out times within  $\pm 200\text{ ps}$  of each other. Switching I/Os are placed outside of the PLL bank. Refer to the "Simultaneously Switching Outputs (SSOs) and Printed Circuit Board Layout" section in the IGLOO nano FPGA Fabric User's Guide.
9. The AGLN010, AGLN015, and AGLN020 devices do not support PLLs.



**Figure 2-38 • FIFO FULL Flag and AFULL Flag Assertion**



**Figure 2-39 • FIFO EMPTY Flag and AEMPTY Flag Deassertion**



**Figure 2-40 • FIFO FULL Flag and AFULL Flag Deassertion**

UC36	
Pin Number	AGLN010 Function
A1	IO21RSB1
A2	IO18RSB1
A3	IO13RSB1
A4	GDC0/IO00RSB0
A5	IO06RSB0
A6	GDA0/IO04RSB0
B1	GEC0/IO37RSB1
B2	IO20RSB1
B3	IO15RSB1
B4	IO09RSB0
B5	IO08RSB0
B6	IO07RSB0
C1	IO22RSB1
C2	GEA0/IO34RSB1
C3	GND
C4	GND
C5	VCCIB0
C6	IO02RSB0
D1	IO33RSB1
D2	VCCIB1
D3	VCC
D4	VCC
D5	IO10RSB0
D6	IO11RSB0
E1	IO32RSB1
E2	FF/IO31RSB1
E3	TCK
E4	VPUMP
E5	TRST
E6	VJTAG
F1	IO29RSB1
F2	IO25RSB1
F3	IO23RSB1
F4	TDI

UC36	
Pin Number	AGLN010 Function
F5	TMS
F6	TDO

CS81	
Pin Number	AGLN030Z Function
A1	IO00RSB0
A2	IO02RSB0
A3	IO06RSB0
A4	IO11RSB0
A5	IO16RSB0
A6	IO19RSB0
A7	IO22RSB0
A8	IO24RSB0
A9	IO26RSB0
B1	IO81RSB1
B2	IO04RSB0
B3	IO10RSB0
B4	IO13RSB0
B5	IO15RSB0
B6	IO20RSB0
B7	IO21RSB0
B8	IO28RSB0
B9	IO25RSB0
C1	IO79RSB1
C2	IO80RSB1
C3	IO08RSB0
C4	IO12RSB0
C5	IO17RSB0
C6	IO14RSB0
C7	IO18RSB0
C8	IO29RSB0
C9	IO27RSB0
D1	IO74RSB1
D2	IO76RSB1
D3	IO77RSB1
D4	VCC
D5	VCCIB0
D6	GND
D7	IO23RSB0
D8	IO31RSB0

CS81	
Pin Number	AGLN030Z Function
D9	IO30RSB0
E1	GEB0/IO71RSB1
E2	GEA0/IO72RSB1
E3	GEC0/IO73RSB1
E4	VCCIB1
E5	VCC
E6	VCCIB0
E7	GDC0/IO32RSB0
E8	GDA0/IO33RSB0
E9	GDB0/IO34RSB0
F1	IO68RSB1
F2	IO67RSB1
F3	IO64RSB1
F4	GND
F5	VCCIB1
F6	IO47RSB1
F7	IO36RSB0
F8	IO38RSB0
F9	IO40RSB0
G1	IO65RSB1
G2	IO66RSB1
G3	IO57RSB1
G4	IO53RSB1
G5	IO49RSB1
G6	IO44RSB1
G7	IO46RSB1
G8	VJTAG
G9	TRST
H1	IO62RSB1
H2	FF/IO60RSB1
H3	IO58RSB1
H4	IO54RSB1
H5	IO48RSB1
H6	IO43RSB1
H7	IO42RSB1

CS81	
Pin Number	AGLN030Z Function
H8	TDI
H9	TDO
J1	IO63RSB1
J2	IO61RSB1
J3	IO59RSB1
J4	IO56RSB1
J5	IO52RSB1
J6	IO45RSB1
J7	TCK
J8	TMS
J9	VPUMP

CS81		CS81		CS81	
Pin Number	AGLN125 Function	Pin Number	AGLN125 Function	Pin Number	AGLN125 Function
A1	GAA0/IO00RSB0	E1	GFB0/IO120RSB1	J1	GEA2/IO103RSB1
A2	GAA1/IO01RSB0	E2	GFB1/IO121RSB1	J2	GEC2/IO101RSB1
A3	GAC0/IO04RSB0	E3	GFA1/IO118RSB1	J3	IO97RSB1
A4	IO13RSB0	E4	VCCIB1	J4	IO93RSB1
A5	IO22RSB0	E5	VCC	J5	IO90RSB1
A6	IO32RSB0	E6	VCCIB0	J6	IO78RSB1
A7	GBB0/IO37RSB0	E7	GCA0/IO56RSB0	J7	TCK
A8	GBA1/IO40RSB0	E8	GCA1/IO55RSB0	J8	TMS
A9	GBA2/IO41RSB0	E9	GCB2/IO58RSB0	J9	VPUMP
B1	GAA2/IO132RSB1	F1*	VCCPLF		
B2	GAB0/IO02RSB0	F2*	VCOMPLF		
B3	GAC1/IO05RSB0	F3	GND		
B4	IO11RSB0	F4	GND		
B5	IO25RSB0	F5	VCCIB1		
B6	GBC0/IO35RSB0	F6	GND		
B7	GBB1/IO38RSB0	F7	GDA1/IO65RSB0		
B8	IO42RSB0	F8	GDC1/IO61RSB0		
B9	GBB2/IO43RSB0	F9	GDC0/IO62RSB0		
C1	GAB2/IO130RSB1	G1	GEA0/IO104RSB1		
C2	IO131RSB1	G2	GEC0/IO108RSB1		
C3	GND	G3	GEB1/IO107RSB1		
C4	IO15RSB0	G4	IO96RSB1		
C5	IO28RSB0	G5	IO92RSB1		
C6	GND	G6	IO72RSB1		
C7	GBA0/IO39RSB0	G7	GDB2/IO68RSB1		
C8	GBC2/IO45RSB0	G8	VJTAG		
C9	IO47RSB0	G9	TRST		
D1	GAC2/IO128RSB1	H1	GEA1/IO105RSB1		
D2	IO129RSB1	H2	FF/GEB2/IO102RSB1		
D3	GFA2/IO117RSB1	H3	IO99RSB1		
D4	VCC	H4	IO94RSB1		
D5	VCCIB0	H5	IO91RSB1		
D6	GND	H6	IO81RSB1		
D7	GCC2/IO59RSB0	H7	GDA2/IO67RSB1		
D8	GCC1/IO51RSB0	H8	TDI		
D9	GCC0/IO52RSB0	H9	TDO		

Note: \* Pin numbers F1 and F2 must be connected to ground because a PLL is not supported for AGLN125-CS81.



QN48	
Pin Number	AGLN010 Function
1	GEC0/IO37RSB1
2	IO36RSB1
3	GEA0/IO34RSB1
4	IO22RSB1
5	GND
6	VCCIB1
7	IO24RSB1
8	IO33RSB1
9	IO26RSB1
10	IO32RSB1
11	IO27RSB1
12	IO29RSB1
13	IO30RSB1
14	FF/IO31RSB1
15	IO28RSB1
16	IO25RSB1
17	IO23RSB1
18	VCC
19	VCCIB1
20	IO17RSB1
21	IO14RSB1
22	TCK
23	TDI
24	TMS
25	VPUMP
26	TDO
27	TRST
28	VJTAG
29	IO11RSB0
30	IO10RSB0
31	IO09RSB0
32	IO08RSB0
33	VCCIB0
34	GND
35	VCC

QN48	
Pin Number	AGLN010 Function
36	IO07RSB0
37	IO06RSB0
38	GDA0/IO05RSB0
39	IO03RSB0
40	GDC0/IO01RSB0
41	IO12RSB1
42	IO13RSB1
43	IO15RSB1
44	IO16RSB1
45	IO18RSB1
46	IO19RSB1
47	IO20RSB1
48	IO21RSB1

VQ100	
Pin Number	AGLN125Z Function
1	GND
2	GAA2/IO67RSB1
3	IO68RSB1
4	GAB2/IO69RSB1
5	IO132RSB1
6	GAC2/IO131RSB1
7	IO130RSB1
8	IO129RSB1
9	GND
10	GFB1/IO124RSB1
11	GFB0/IO123RSB1
12	VCOMPLF
13	GFA0/IO122RSB1
14	VCCPLF
15	GFA1/IO121RSB1
16	GFA2/IO120RSB1
17	VCC
18	VCCIB1
19	GEC0/IO111RSB1
20	GEB1/IO110RSB1
21	GEB0/IO109RSB1
22	GEA1/IO108RSB1
23	GEA0/IO107RSB1
24	VMV1
25	GNDQ
26	GEA2/IO106RSB1
27	FF/GEB2/IO105RSB1
28	GEC2/IO104RSB1
29	IO102RSB1
30	IO100RSB1
31	IO99RSB1
32	IO97RSB1
33	IO96RSB1
34	IO95RSB1
35	IO94RSB1

VQ100	
Pin Number	AGLN125Z Function
36	IO93RSB1
37	VCC
38	GND
39	VCCIB1
40	IO87RSB1
41	IO84RSB1
42	IO81RSB1
43	IO75RSB1
44	GDC2/IO72RSB1
45	GDB2/IO71RSB1
46	GDA2/IO70RSB1
47	TCK
48	TDI
49	TMS
50	VMV1
51	GND
52	VPUMP
53	NC
54	TDO
55	TRST
56	VJTAG
57	GDA1/IO65RSB0
58	GDC0/IO62RSB0
59	GDC1/IO61RSB0
60	GCC2/IO59RSB0
61	GCB2/IO58RSB0
62	GCA0/IO56RSB0
63	GCA1/IO55RSB0
64	GCC0/IO52RSB0
65	GCC1/IO51RSB0
66	VCCIB0
67	GND
68	VCC
69	IO47RSB0
70	GBC2/IO45RSB0

VQ100	
Pin Number	AGLN125Z Function
71	GBB2/IO43RSB0
72	IO42RSB0
73	GBA2/IO41RSB0
74	VMV0
75	GNDQ
76	GBA1/IO40RSB0
77	GBA0/IO39RSB0
78	GBB1/IO38RSB0
79	GBB0/IO37RSB0
80	GBC1/IO36RSB0
81	GBC0/IO35RSB0
82	IO32RSB0
83	IO28RSB0
84	IO25RSB0
85	IO22RSB0
86	IO19RSB0
87	VCCIB0
88	GND
89	VCC
90	IO15RSB0
91	IO13RSB0
92	IO11RSB0
93	IO09RSB0
94	IO07RSB0
95	GAC1/IO05RSB0
96	GAC0/IO04RSB0
97	GAB1/IO03RSB0
98	GAB0/IO02RSB0
99	GAA1/IO01RSB0
100	GAA0/IO00RSB0

VQ100	
Pin Number	AGLN250 Function
1	GND
2	GAA2/IO67RSB3
3	IO66RSB3
4	GAB2/IO65RSB3
5	IO64RSB3
6	GAC2/IO63RSB3
7	IO62RSB3
8	IO61RSB3
9	GND
10	GFB1/IO60RSB3
11	GFB0/IO59RSB3
12	VCOMPLF
13	GFA0/IO57RSB3
14	VCCPLF
15	GFA1/IO58RSB3
16	GFA2/IO56RSB3
17	VCC
18	VCCIB3
19	GFC2/IO55RSB3
20	GEC1/IO54RSB3
21	GEC0/IO53RSB3
22	GEA1/IO52RSB3
23	GEA0/IO51RSB3
24	VMV3
25	GNDQ
26	GEA2/IO50RSB2
27	FF/GEA2/IO49RSB2
28	GEC2/IO48RSB2
29	IO47RSB2
30	IO46RSB2
31	IO45RSB2
32	IO44RSB2
33	IO43RSB2
34	IO42RSB2
35	IO41RSB2
36	IO40RSB2

VQ100	
Pin Number	AGLN250 Function
37	VCC
38	GND
39	VCCIB2
40	IO39RSB2
41	IO38RSB2
42	IO37RSB2
43	GDC2/IO36RSB2
44	GDB2/IO35RSB2
45	GDA2/IO34RSB2
46	GNDQ
47	TCK
48	TDI
49	TMS
50	VMV2
51	GND
52	VPUMP
53	NC
54	TDO
55	TRST
56	VJTAG
57	GDA1/IO33RSB1
58	GDC0/IO32RSB1
59	GDC1/IO31RSB1
60	IO30RSB1
61	GCB2/IO29RSB1
62	GCA1/IO27RSB1
63	GCA0/IO28RSB1
64	GCC0/IO26RSB1
65	GCC1/IO25RSB1
66	VCCIB1
67	GND
68	VCC
69	IO24RSB1
70	GBC2/IO23RSB1
71	GBC2/IO22RSB1
72	IO21RSB1

VQ100	
Pin Number	AGLN250 Function
73	GBA2/IO20RSB1
74	VMV1
75	GNDQ
76	GBA1/IO19RSB0
77	GBA0/IO18RSB0
78	GGB1/IO17RSB0
79	GGB0/IO16RSB0
80	GBC1/IO15RSB0
81	GBC0/IO14RSB0
82	IO13RSB0
83	IO12RSB0
84	IO11RSB0
85	IO10RSB0
86	IO09RSB0
87	VCCIB0
88	GND
89	VCC
90	IO08RSB0
91	IO07RSB0
92	IO06RSB0
93	GAC1/IO05RSB0
94	GAC0/IO04RSB0
95	GAB1/IO03RSB0
96	GAB0/IO02RSB0
97	GAA1/IO01RSB0
98	GAA0/IO00RSB0
99	GNDQ
100	VMV0

Revision	Changes	Page
Revision 11 (Jul 2010)	The status of the AGLN060 device has changed from Advance to Production.	III
	The values for PAC1, PAC2, PAC3, and PAC4 were updated in Table 2-15 • Different Components Contributing to Dynamic Power Consumption in IGLOO nano Devices for 1.5 V core supply voltage (SAR 26404).	2-10
	The values for PAC1, PAC2, PAC3, and PAC4 were updated in Table 2-17 • Different Components Contributing to Dynamic Power Consumption in IGLOO nano Devices for 1.2 V core supply voltage (SAR 26404).	2-11
July 2010	The versioning system for datasheets has been changed. Datasheets are assigned a revision number that increments each time the datasheet is revised. The "IGLOO nano Device Status" table on page III indicates the status for each device in the device family.	N/A
Revision 10 (Apr 2010)	References to differential inputs were removed from the datasheet, since IGLOO nano devices do not support differential inputs (SAR 21449).	N/A
	A parenthetical note, "hold previous I/O state in Flash*Freeze mode," was added to each occurrence of bus hold in the datasheet (SAR 24079).	N/A
	The "In-System Programming (ISP) and Security" section was revised to add 1.2 V programming.	I
	The note connected with the "IGLOO nano Ordering Information" table was revised to clarify features not available for Z feature grade devices.	IV
	The "IGLOO nano Device Status" table is new.	III
	The definition of C in the "Temperature Grade Offerings" table was changed to "extended commercial temperature range".	VI
	1.2 V wide range was added to the list of voltage ranges in the "I/Os with Advanced I/O Standards" section.	1-8
	A note was added to Table 2-2 • Recommended Operating Conditions <sup>1</sup> regarding switching from 1.2 V to 1.5 V core voltage for in-system programming. The VJTAG voltage was changed from "1.425 to 3.6" to "1.4 to 3.6" (SAR 24052). The note regarding voltage for programming V2 and V5 devices was revised (SAR 25213). The maximum value for VPUMP programming voltage (operation mode) was changed from 3.45 V to 3.6 V (SAR 25220).	2-2
	Table 2-6 • Temperature and Voltage Derating Factors for Timing Delays (normalized to TJ = 70°C, VCC = 1.425 V) and Table 2-7 • Temperature and Voltage Derating Factors for Timing Delays (normalized to TJ = 70°C, VCC = 1.14 V) were updated. Table 2-8 • Power Supply State per Mode is new.	2-6, 2-7
	The tables in the "Quiescent Supply Current" section were updated (SAR 24882 and SAR 24112).	2-7
	VJTAG was removed from Table 2-10 • Quiescent Supply Current (IDD) Characteristics, IGLOO nano Sleep Mode* (SARs 24112, 24882, and 79503).	2-8
	The note stating what was included in I <sub>DD</sub> was removed from Table 2-11 • Quiescent Supply Current (IDD) Characteristics, IGLOO nano Shutdown Mode. The note, "per VCCI or VJTAG bank" was removed from Table 2-12 • Quiescent Supply Current (IDD), No IGLOO nano Flash*Freeze Mode <sup>1</sup> . The note giving I <sub>DD</sub> was changed to "I <sub>DD</sub> = N <sub>BANKS</sub> * I <sub>CCI</sub> + I <sub>CCA</sub> ".	2-8
	The values in Table 2-13 • Summary of I/O Input Buffer Power (per pin) – Default I/O Software Settings and Table 2-14 • Summary of I/O Output Buffer Power (per pin) – Default I/O Software Settings <sup>1</sup> were updated. Wide range support information was added.	2-9

Revision / Version	Changes	Page
<b>Revision 2 (Dec 2008)</b> Product Brief Advance v0.4  Packaging Advance v0.3	The second table note in "IGLOO nano Devices" table was revised to state, "AGLN060, AGLN125, and AGLN250 in the CS81 package do not support PLLs. AGLN030 and smaller devices do not support this feature."	II
	The I/Os per package for CS81 were revised to 60 for AGLN060, AGLN125, and AGLN250 in the "I/Os Per Package" table.	II
	The "UC36" pin table is new.	4-2
<b>Revision 1 (Nov 2008)</b> Product Brief Advance v0.3	The "Advanced I/Os" section was updated to include wide power supply voltage support for 1.14 V to 1.575 V.	I
	The AGLN030 device was added to product tables and replaces AGL030 entries that were formerly in the tables.	VI
	The "I/Os Per Package" table was updated for the CS81 package to change the number of I/Os for AGLN060, AGLN125, and AGLN250 from 66 to 64.	II
	The "Wide Range I/O Support" section is new.	1-8
	The table notes and references were revised in Table 2-2 • Recommended Operating Conditions <sup>1</sup> . VMV was included with VCCI and a table note was added stating, "VMV pins must be connected to the corresponding VCCI pins. See <i>Pin Descriptions</i> for further information." Please review carefully.	2-2
	VJTAG was added to the list in the table note for Table 2-9 • Quiescent Supply Current (IDD) Characteristics, IGLOO nano Flash*Freeze Mode*. Values were added for AGLN010, AGLN015, and AGLN030 for 1.5 V.	2-7
	VCCI was removed from the list in the table note for Table 2-10 • Quiescent Supply Current (IDD) Characteristics, IGLOO nano Sleep Mode*.	2-8
	Values for I <sub>CCA</sub> current were updated for AGLN010, AGLN015, and AGLN030 in Table 2-12 • Quiescent Supply Current (IDD), No IGLOO nano Flash*Freeze Mode <sup>1</sup> .	2-8
	Values for PAC1 and PAC2 were added to Table 2-15 • Different Components Contributing to Dynamic Power Consumption in IGLOO nano Devices and Table 2-17 • Different Components Contributing to Dynamic Power Consumption in IGLOO nano Devices.	2-10, 2-11
	Table notes regarding wide range support were added to Table 2-21 • Summary of Maximum and Minimum DC Input and Output Levels.	2-19
	1.2 V LVCMOS wide range values were added to Table 2-22 • Summary of Maximum and Minimum DC Input Levels and Table 2-23 • Summary of AC Measuring Points.	2-19, 2-20
	The following table note was added to Table 2-25 • Summary of I/O Timing Characteristics—Software Default Settings and Table 2-26 • Summary of I/O Timing Characteristics—Software Default Settings: "All LVCMOS 3.3 V software macros support LVCMOS 3.3 V wide range, as specified in the JESD8-B specification."	2-21
	3.3 V LVCMOS Wide Range and 1.2 V Wide Range were added to Table 2-28 • I/O Output Buffer Maximum Resistances <sup>1</sup> and Table 2-30 • I/O Short Currents IOSH/IOSL.	2-23, 2-24